

<b>Notice of References Cited</b>	Application/Control No. 10/730,467	Applicant(s)/Patent Under Reexamination TU ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,237,058 B1	05-2001	Nakagawa, Toshikazu	710/260
	B	US-6,265,885 B1	07-2001	Luo et al.	324/719
	C	US-6,813,665 B2	11-2004	Rankin et al.	710/260
	D	US-6,219,741 B1	04-2001	Pawlowski et al.	710/260
	E	US-6,189,065 B1	02-2001	Arndt et al.	710/260
	F	US-5,382,950 A	01-1995	Gronemeyer, Michael	340/825.5
	G	US-2003/0105798 A1	06-2003	Kim et al.	709/105
	H	US-5,446,910 A	08-1995	Kennedy et al.	710/119
	I	US-2003/0120702 A1	06-2003	Jahnke, Steven R.	709/102
	J	US-2005/0078694 A1	04-2005	Oner, Koray	370/412
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-329022	12-1996	Japan	Tomota Masanori	G06F 15/16
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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